

#### Integrated Service Technology Inc.

Reliability & Failure Analysis Group

1F Xinyicheng C Building, No.1618 Yishan Rd., Shanghai City, China.

Tel: 86-21-61910691, Fax: 86-21-64069790

http://www.istgroup.com

Page 1 of 7

Report No.: SH2004260018LE-CN

Version: A

## LATCH UP TEST REPORT

Company : 南京凌鸥创芯电子有限公司

Address : 南京栖霞区兴智路 6 号兴智科技园 C 栋 1310 室

Model Name : LKS32MC051

Date Received : April 29, 2020

Date Tested : April 29, 2020

## **TESTING LABORATORY IS APPROVEDED BY:**

IECQ Certificate of Approval No.: IECQ-L DEKRA 17.0004 For Independent Test Laboratory According to ISO/IEC 17025

## **WE HEREBY CERTIFY THAT:**

The test(s) shown in the attachment were conducted according to the indicating procedures. We assume full responsibility for the accuracy and completeness of these tests and vouch for the qualifications of all personnel performing them.

	Name	Signature	Date
Testing Engineer	Peng_Zhao	Peng_zhao	2020/4/29
Approving Manager	Kimi Lai	Kimi_Lai	2020/4/29

### Note:

- 1. This report will be invalid if reproduced in whole or in part.
- 2. This report refers only to the specimen(s) submitted to test, and is included as depositely.
- 3. This report is ONLY valid with the examination seal and signature.
- The tested specimen(s) will only be preserved for thirty days from the date issued, if not collected by the applicant.



#### Integrated Service Technology Inc.

Reliability & Failure Analysis Group

1F Xinyicheng C Building, No.1618 Yishan Rd., Shanghai City, China.

Tel: 86-21-61910691, Fax: 86-21-64069790

http://www.istgroup.com

## Page 2 of 7

Report No.: SH2004260018LE-CN

Version: A

## **TABLE OF CONTENTS**

I. GENERAL INFORMATION	
1.1 DESCRIPTION OF UNIT	3
2. LATCH UP TEST	
2.1 TEST EQUIPMENT	4
2.2 LABORATORY AMBIENCE CONDITION	4
2.3 REFERENCE DOCUMENT	4
2.4 TEST CONDITION	4
2.5 SUMMARY OF TEST	4
2.6 CONTENTS OF TEST	5



#### Integrated Service Technology Inc.

Reliability & Failure Analysis Group

1F Xinyicheng C Building, No.1618 Yishan Rd., Shanghai City, China.

Tel: 86-21-61910691, Fax: 86-21-64069790

http://www.istgroup.com

## 1. GENERAL INFORMATION

## 1.1 DESCRIPTION OF UNIT

MANUFACTURER : 南京凌鸥创芯电子有限公司

DEVICE NAME : LKS32MC051

PACKAGED / PIN COUNT : QFP48

REFERENCE DOCUMENT : JEDEC EIA/JESD78E

TRIGGER CURRENT : 100mA (±); 200mA (±)

V SUPPLY OVER VOLTAGE TEST : 5.5V~8V, Step: 0.5V(+);

TEST TEMPERATURE : ROOM TEMPERATURE

PULSE DURATION : 10 ms SAMPLE QUANTITY : 3 pcs

: If absolute Inom is < 25 mA, then absolute Inom + 10mA is used;

Report No.: SH2004260018LE-CN

Page 3 of 7

Version: A

FAILURE CRITERIA O

If absolute Inom is > 25 mA, then > 1.4X absolute Inom is used;

#### Integrated Service Technology Inc.

Reliability & Failure Analysis Group

1F Xinyicheng C Building, No.1618 Yishan Rd., Shanghai City, China.

Tel: 86-21-61910691, Fax: 86-21-64069790

http://www.istgroup.com

#### Page 4 of 7

Report No.: SH2004260018LE-CN

Version: A

## 2. LATCH UP TEST

## 2.1 TEST EQUIPMENT

Test Equipment	Equipment S/N	Calibration Date:	Recommended Due Date:
KEYTEK ZAPMASTER MK2 768	1102174	July 9, 2019	July 8, 2020

## 2.2 LABORATORY AMBIENCE CONDITION

Temperature: 25±5°C

Relative humidity: 55%±10% (RH)

## 2.3 REFERENCE DOCUMENT

The test is based on JEDEC EIA/JESD78E

## 2.4 TEST CONDITION

I Trigger

Over Voltage Test

## 2.5 SUMMARY OF TEST

Trigger Mode	Test Pin	Sample Quantity	Tested Result	V or I Limits	l Trigger : Class <u>I A</u>
l Trigger (+)	I/O5.5V		PASS +200mA	+8V	Temperature Classification: CLASS I: For Latch-up test at room
I Trigger (-)	I/O5.5V	3	PASS -200mA		The fractional temperature temperature  CLASSII: For Latch-up test at room temperature ambientemperature  A: ≥100mA  B: Other
Over Volt Test V <sub>supply</sub>	VCC5.5V		PASS +8V	+600mA	

Group Set	Pin List
I/O5.5V	1,2,5-48
VCC5.5V	4
VSS	3

#### Integrated Service Technology Inc.

Reliability & Failure Analysis Group

1F Xinyicheng C Building, No.1618 Yishan Rd., Shanghai City, China.

Tel: 86-21-61910691, Fax: 86-21-64069790

http://www.istgroup.com

## 2.6 CONTENTS OF TEST

	I Trigge	er (Positive)			
	Sample No. & Failed current (mA)				
Tested Pin	#23	#24	#25		
1	PASS+200mA	PASS+200mA	PASS+200mA		
2	PASS+200mA	PASS+200mA	PASS+200mA		
5	PASS+200mA	PASS+200mA	PASS+200mA		
6	PASS+200mA	PASS+200mA	PASS+200mA		
7	PASS+200mA	PASS+200mA	PASS+200mA		
8	PASS+200mA	PASS+200mA	PASS+200mA		
9	PASS+200mA	PASS+200mA	PASS+200mA		
10	PASS+200mA	PASS+200mA	PASS+200mA		
11	PASS+200mA	PASS+200mA	PASS+200mA		
12	PASS+200mA	PASS+200mA	PASS+200mA		
13	PASS+200mA	PASS+200mA	PASS+200mA		
14	PASS+200mA	PASS+200mA	PASS+200mA		
15	PASS+200mA	PASS+200mA	PASS+200mA		
16	PASS+200mA	PASS+200mA	PASS+200mA		
17	PASS+200mA	PASS+200mA	PASS+200mA		
18	PASS+200mA	PASS+200mA	PASS+200mA		
19	PASS+200mA	PASS+200mA	PASS+200mA		
20	PASS+200mA	PASS+200mA	PASS+200mA		
21	PASS+200mA	PASS+200mA	PASS+200mA		
22	PASS+200mA	PASS+200mA	PASS+200mA		
23	PASS+200mA	PASS+200mA	PASS+200mA		
24	PASS+200mA	PASS+200mA	PASS+200mA		
25	PASS+200mA	PASS+200mA	PASS+200mA		
26	PASS+200mA	PASS+200mA	PASS+200mA		
27	PASS+200mA	PASS+200mA	PASS+200mA		
28	PASS+200mA	PASS+200mA	PASS+200mA		
29	PASS+200mA	PASS+200mA	PASS+200mA		
30	PASS+200mA	PASS+200mA	PASS+200mA		
31	PASS+200mA	PASS+200mA	PASS+200mA		
32	PASS+200mA	PASS+200mA	PASS+200mA		
33	PASS+200mA	PASS+200mA	PASS+200mA		
34	PASS+200mA	PASS+200mA	PASS+200mA		
35	PASS+200mA	PASS+200mA	PASS+200mA		
36	PASS+200mA	PASS+200mA	PASS+200mA		
37	PASS+200mA	PASS+200mA	PASS+200mA		
38	PASS+200mA	PASS+200mA	PASS+200mA		
39	PASS+200mA	PASS+200mA	PASS+200mA		
40	PASS+200mA	PASS+200mA	PASS+200mA		
41	PASS+200mA	PASS+200mA	PASS+200mA		
42	PASS+200mA	PASS+200mA	PASS+200mA		
43	PASS+200mA	PASS+200mA	PASS+200mA		

Page 5 of 7

Report No.: SH2004260018LE-CN

Version: A

### Integrated Service Technology Inc.

Reliability & Failure Analysis Group

1F Xinyicheng C Building, No.1618 Yishan Rd., Shanghai City, China.

Tel: 86-21-61910691, Fax: 86-21-64069790

http://www.istgroup.com

Version: A a. Page 6 of 7

Report No.: SH2004260018LE-CN

44	PASS+200mA	PASS+200mA	PASS+200mA
45	PASS+200mA	PASS+200mA	PASS+200mA
46	PASS+200mA	PASS+200mA	PASS+200mA
47	PASS+200mA	PASS+200mA	PASS+200mA
48	PASS+200mA	PASS+200mA	PASS+200mA

	I Trigge	r (Negative)			
Tested Pin	Sample No. & Failed current (mA)				
rested Fill	#23	#24	#25		
1	PASS-200mA	PASS-200mA	PASS-200mA		
2	PASS-200mA	PASS-200mA	PASS-200mA		
5	PASS-200mA	PASS-200mA	PASS-200mA		
6	PASS-200mA	PASS-200mA	PASS-200mA		
7	PASS-200mA	PASS-200mA	PASS-200mA		
8	PASS-200mA	PASS-200mA	PASS-200mA		
9	PASS-200mA	PASS-200mA	PASS-200mA		
10	PASS-200mA	PASS-200mA	PASS-200mA		
11	PASS-200mA	PASS-200mA	PASS-200mA		
12	PASS-200mA	PASS-200mA	PASS-200mA		
13	PASS-200mA	PASS-200mA	PASS-200mA		
14	PASS-200mA	PASS-200mA	PASS-200mA		
15	PASS-200mA	PASS-200mA	PASS-200mA		
16	PASS-200mA	PASS-200mA	PASS-200mA		
17	PASS-200mA	PASS-200mA	PASS-200mA		
18	PASS-200mA	PASS-200mA	PASS-200mA		
19	PASS-200mA	PASS-200mA	PASS-200mA		
20	PASS-200mA	PASS-200mA	PASS-200mA		
21	PASS-200mA	PASS-200mA	PASS-200mA		
22	PASS-200mA	PASS-200mA	PASS-200mA		
23	PASS-200mA	PASS-200mA	PASS-200mA		
24	PASS-200mA	PASS-200mA	PASS-200mA		
25	PASS-200mA	PASS-200mA	PASS-200mA		
26	PASS-200mA	PASS-200mA	PASS-200mA		
27	PASS-200mA	PASS-200mA	PASS-200mA		
28	PASS-200mA	PASS-200mA	PASS-200mA		
29	PASS-200mA	PASS-200mA	PASS-200mA		
30	PASS-200mA	PASS-200mA	PASS-200mA		
31	PASS-200mA	PASS-200mA	PASS-200mA		
32	PASS-200mA	PASS-200mA	PASS-200mA		
33	PASS-200mA	PASS-200mA	PASS-200mA		
34	PASS-200mA	PASS-200mA	PASS-200mA		
35	PASS-200mA	PASS-200mA	PASS-200mA		
36	PASS-200mA	PASS-200mA	PASS-200mA		
37	PASS-200mA	PASS-200mA	PASS-200mA		

#### Integrated Service Technology Inc.

Reliability & Failure Analysis Group

1F Xinyicheng C Building, No.1618 Yishan Rd., Shanghai City, China.

Tel: 86-21-61910691, Fax: 86-21-64069790

http://www.istgroup.com

Version: A a. Page 7 of 7

Report No.: SH2004260018LE-CN

38	PASS-200mA	PASS-200mA	PASS-200mA
39	PASS-200mA	PASS-200mA	PASS-200mA
40	PASS-200mA	PASS-200mA	PASS-200mA
41	PASS-200mA	PASS-200mA	PASS-200mA
42	PASS-200mA	PASS-200mA	PASS-200mA
43	PASS-200mA	PASS-200mA	PASS-200mA
44	PASS-200mA	PASS-200mA	PASS-200mA
45	PASS-200mA	PASS-200mA	PASS-200mA
46	PASS-200mA	PASS-200mA	PASS-200mA
47	PASS-200mA	PASS-200mA	PASS-200mA
48	PASS-200mA	PASS-200mA	PASS-200mA

Over Voltage Test for V <sub>supply</sub>				
Tested Pin	Sample No. & Failed Volt (V)			
rested Fill	#23	#24	#25	
4	PASS+8V PASS+8V PASS+8V			